

ABSTRACT

The present invention relates to a technique for analyzing
5 a sample by utilizing a double integration circuit (11) for
outputting a physical quantity related to the output from an
analytical tool (2). In the present invention, the time
interval from when the output from the analytical tool (2) is
inputted into the double integration circuit (11) till when
10 the physical quantity is started to be outputted from the double
integration circuit (11) differs before and after the supply
of the sample to the analytical tool (2) is confirmed.